


Search Notes 	Application/Control No. 10639925	Applicant(s)/Patent Under Reexamination PREIKSZAS ET AL.
	Examiner TOAN M LE	Art Unit 2863

SEARCHED			
Class	Subclass	Date	Examiner
702	107, 85	2/11/08	TL
250	396R, 201.3, 311	2/11/08	TL
359	383, 17	2/11/08	TL
382	255	2/11/08	TL
Above	Updated	12/16/08	TL

SEARCH NOTES		
Search Notes	Date	Examiner
702/107, 85; 250/396R, 201.3, 311; 359/383, 17; 382/255 (Electron Microscope Tune Index Interpolation)	2/11/08	TL
Electron Microscope Tune Index Interpolate	2/11/08	TL
East- See Search History Printout	2/13/08	TL
IEEE Xplore, ScienceDirect, Web Search	2/13/08	TL
Above Updated	12/16/08	TL
East- See Search History Printout	12/16/08	TL

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
702	107	12/16/08	TL
250	311	12/16/08	TL

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